PCN Number:		20140327001						PCN Date:		03/31/2014		
Title: Qualification of TI Clark as Alternate Assembly/Test site for select WSON Devices												
Customer Contact:		PCN Manager			Phone:	+1(214)480-6037			Dept:	Quality Services		
Proposed 1st Ship Da		te:	(07/01/2014 Estima		ated Sample Avail		Availa	bility:	03/31/2014		
Change	Туре:											
Assembly Site			Assembly Process				Assembly Materials					
Desi	gn			Electrical S	Specificat	ion		Mec	lechanical Specification			
	Site			Packing/Shipping/Labeling Tes				Test	st Process			
Wafe	er Bump Site			Wafer Bun	mp Material Wa			Wafe	fer Bump Process			
Wafer Fab Site				Wafer Fab Materials			Wafe	Wafer Fab Process				
			Part number change									
					PCN De	etails						
Description of Change:												
Texas Instruments is pleased to announce the qualification of CLARK AT as an alternate assembly and test site for the Select WSON devices. The material set between the existing and new site are the same.												
Reason for Change:												
Continuity of Supply												
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):												
None												

Changes to product identification resulting from this PCN:

Assembly Site		
UTAC	Assembly Site Origin (22L)	ASO: NSE
CLARK-AT	Assembly Site Origin (22L)	ASO: QAB

Sample product shipping label (not actual product label)



Topside Device marking:

Assembly site code for NSE= J Assembly site code for QAB= I

Product Affected						
TLV62080DSGR	TPS62080DSGR	TPS62081DSGR	TPS62082DSGR			
TLV62080DSGT	TPS62080DSGT	TPS62081DSGT	TPS62082DSGT			

Qualification Data - Approved September, 2011							
This qualification has been developed for the validation of this change. The qualification data							
validates that the propos	sed change meets t	he applicable released	technical spe	ecificatio	ns.		
Qual Vehicle#1: TPS62750DSK (MSL 1-260C)							
Package Construction Details							
Assembly Site:	CLARK AT	Mold Compound:	4208625				
# Pins-Designator, Family:	10-DSK, WSON	Mount Compound:	4207768				
Lead Finish	NiPdAu	Bond Wire:	1.31mil Cu				
Qualification: Plan Test Results							
Dolinhility Toot	Conditions	Conditions		Sample Size/Fail			
Reliability Test	Conditions			Lot#2	Lot#3		
**High Temp. Storage Bake	170C (420hrs)	170C (420hrs)		77/0	77/0		
**Autoclave 121C	121C, 2 ATM (9	121C, 2 ATM (96 hrs)		77/0	77/0		
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
Visual / Mechanical	Per Manufacturing specifications		pass	pass	pass		
Solderability	Steam age, 8 h	Steam age, 8 hours			pass		
Notes **- Preconditioning sequence: Level 1-260C.							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com